

Search Notes



Application/Control No.

10/632,176

Examiner

Donghee Kang

Applicant(s)/Patent under Reexamination

FARROKH ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	441-417 622	11-15-04	Kang
438	22, 50 52, 53	11-15-04	Kang
338	186-192	11-15-04	Kang
updated search		05-06-05	Kang
307	110	05-06-05	Kang
updated search		10-26-05	Kang

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
257	414-417	10-26-05	Kang
438	22, 50 52, 53	10-26-05	Kang
Pub text search see interference search printout		10-26-05	Kang

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East US PAT, US PGPub, EPD TPI, New, IBMTDB	11-15-04	Kang
text search see attached search history	11-15-04 05-06-05	Kang Kang
NPL IEEE Explore	05-06-05	Kang